FCC ID: 2AXP2-GK25

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]· $[\sqrt{f(GHZ)}] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BLE:

Modulation	Channel Freq. (GHz)	Conducte d power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
BLE(1M)	2.402	-4.97	0.32	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.440	-5.14	0.31	-5±1	-4	0.40	<5	0.12437	3.00	YES
	2.480	-5.69	0.27	-5±1	-4	0.40	<5	0.12539	3.00	YES
BLE(2M)	2.402	-4.97	0.32	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.440	-5.12	0.31	-5±1	-4	0.40	<5	0.12437	3.00	YES
	2.480	-5.71	0.27	-5±1	-4	0.40	<5	0.12539	3.00	YES

SRD 2.4G

Modulation	Channel Freq. (GHz)	Conducte d power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
	2.402	-1.15	0.77	-2±1	-1	0.79	<5	0.24622	3.00	YES
GFSK	2.446	-1.8	0.66	-2±1	-1	0.79	<5	0.24846	3.00	YES
	2.479	-2.58	0.55	-3±1	-2	0.63	<5	0.19869	3.00	YES

Note: This product does not support the requirements under 2.4G multiple sources.

Conclusion:

Alex Li

For the max result : $0.24846 \le 3.0$ for 1g SAR, SAR is not required.

Signature: Date: 8/16/2024

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